

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/721,380	KIM, TAE-KON
Examiner	Art Unit	
German Viana Di Prisco	2617	

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	1/11/2008	GV
inventor name and Assignee search in PALM ExPO and EAST	1/11/2008	GV
IEEE Xplore(http://ieeexplore.ieee.org/Xplore/DynWel.jsp)	1/11/2008	GV
Korea Institute of Patent Information http://eng.kipris.or.kr/	1/11/2008	GV
Consulted with Rafael Perez-Gutierrez Ken Vanderpuye and Duc Nguyen	1/11/2008	GV
EPO Database(http://eo.espacenet.com)	1/11/2008	GV
(point adj coordinator or pc) and (cfp or (contention adj free adj period)) and queue	1/11/2008	GV